

Search Notes

Application/Control No.

10/511,792

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

RADENNE ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E21.501, E23.064 & E23.14	7/16/2007	C.C.
257	681	7/16/2007	C.C.
438	492	7/16/2007	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	7/16/2007	C.C.